



Intel[®] 855GME and Intel[®] 852GME Chipset Memory Controller Hub (MCH)

Thermal Design Guide for Embedded Applications

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Contents

1	Introduction	6
1.1	Document Objective	6
1.2	Terminology	6
1.3	Reference Documents	7
2	Mechanical Reference	8
2.1	Intel® 855GME and Intel® 852GME Chipset MCH Package	8
3	Computational Fluid Dynamics (CFD) Modeling	10
3.1	855GM MCH Thermal Model.....	10
3.2	Thermal Design Power (TDP) Values.....	11
3.3	Maximum Temperature Specification	11
3.4	Modeling Assumptions.....	11
3.5	Modeling Results – 855GME MCH.....	12
3.6	Modeling Results – 852GME	13
3.7	CFD Modeling Conclusions	13
4	Reference Thermal Solution for 1U Applications	14
4.1	Applications	14
4.2	Required Volumetric Keepout.....	14
4.3	Heatsink Assembly	16
4.4	Mechanical Retention	17
4.5	Thermal Interface Material (TIM) and Thermal Bond Line	18
4.6	Solder Joint Protection.....	18
4.7	1U Reference Thermal Solution Mechanical Drawings	19
5	Reference Thermal Solution for CompactPCI* and Blade Applications	20
5.1	Applications	20
5.2	CompactPCI* Heatsink Thermal Performance	20
5.3	Required Volumetric Keepout.....	21
5.4	CompactPCI* Heatsink Assembly	22
5.5	Mechanical Retention	23
5.6	Thermal Interface Material (TIM) and Thermal Bond Line	23
5.7	CompactPCI* Thermal Solution Mechanical Drawings.....	24
6	Temperature Measurement Metrology	25
6.1	Case Temperature Measurements	25
6.2	0 Degree Angle Attach Methodology	25
6.3	Maximum Temperature Specification	26
7	Thermal Management Features and Tools	27
7.1	Internal Temperature Sensor	27
7.2	External Temperature Sensor.....	27
7.3	TDP chipset MCH Stress Application	28
7.4	Memory Thermal Management Software	28
7.5	Thermal Throttling.....	29
7.5.1	Bandwidth Triggered Throttling.....	29

7.5.2	Temperature Triggered Throttling.....	31
8	Thermal/Mechanical Applications.....	33
8.1	Thermal Interface Materials.....	33
8.1.1	Estimate Thermal Resistance.....	33
8.2	Mechanical Loading.....	34
8.3	Thermal and Mechanical Reliability.....	34
9	Summary.....	35

Figures

1	855GME and 852GME chipset MCH Package Dimensions (mm) – Top View	8
2	855GME and 852GME Chipset MCH Package Dimensions (mm) - Side View	9
3	Package Construction Overview	10
4	855GM MCH Thermal Model.....	10
5	855GME MCH (4.3W) Junction Temperatures vs. Airflow	12
6	852GME Airflow Modeling Results.....	13
7	1U Reference Thermal Solution Volumetric Keepout.....	15
8	1U Heatsink Assembly (Heatsink, Clip Frame, and Clip Lever)	16
9	1U Heatsink Assembly Placement and Actuation	16
10	1U Heatsink Clip Assembly	17
11	1U Heatsink Clip Lateral Retention Tab Feature.....	18
12	1U Heatsink Clip Frame and Lever	19
13	CompactPCI* Heatsink Thermal Performance	21
14	CompactPCI* Thermal Solution Volumetric Keepout	22
15	CompactPCI* Heatsink Assembly (Heatsink, Pull-tab, and TIM)	23
16	0 Degree Angle Attach Heatsink Modifications (not to scale).....	26
17	0 Degree Angle Attach Methodology (not to scale)	26
18	External Temperature Sensor	27
19	855GME/852GME chipset MCH Bandwidth Throttling.....	30
20	855GME/852GME chipset MCH Temperature Throttling	31
21	Board Keep-Out Region for 1U Reference Design Heatsink and Mounting Anchor Placement	39
22	CompactPCI* Heatsink Assembly	40

Tables

1	Related reference documents	7
2	855GME and 852GME MCH Thermal Design Power	11
3	855GME and 852GME Chipset MCHs Maximum Temperature Value.....	11
4	855GME and 852GME chipset MCH Maximum Case Temperature Value.....	26
5	Reliability Validation	34
6	1U Reference Design Heatsink Assembly Suppliers (as referenced in Section 4)	36
7	CompactPCI* Reference Design Heatsink Assembly Suppliers (as referenced in Section 5) ...	36
8	Mechanical Drawing List.....	38

Revision History

Date	Revision	Description
October 2003	001	Initial public release of this document.

Introduction

1

1.1 Document Objective

This document is intended to aid system designers to properly implement a thermal management design to ensure reliable and efficient operation of the Intel® 855GME and Intel® 852GME chipset memory controller hubs (MCHs). The objective of thermal management for chipset MCHs is to ensure that the temperature of product while operating in an embedded system is maintained within functional limits. The functional temperature limit is the range within which the electrical circuits within the silicon can be expected to meet specified performance requirements. Operation outside the functional limit can degrade system performance, cause logic errors, or cause component and/or system damage. Temperatures exceeding the maximum operating limits may result in irreversible changes in the operating characteristics of the components. This document will provide an understanding of the operating limits of the Intel® 855GME and Intel® 852GME chipset MCHs and suggest proper thermal design techniques based on a particular configuration.

1.2 Terminology

Term	Definition
DDR	Double Data Rate
FCBGA	Flip Chip Ball Grid Array. A package type defined by a plastic substrate on to which a die is mounted using an underfill C4 (Controlled Collapse Chip Connection) attach style. The primary electrical interface is an array of solder balls attached to the substrate opposite the die.
Junction	Refers to a P-N junction on the silicon. In this document it is used as a temperature reference point for the hottest point on the die (e.g., θ_{j-a} refers to the junction to ambient thermal resistance).
PCB	Printed Circuit Board
Tcase	The measured temperature of a component at the geometric center of the top of the die.
TDP	Thermal Design Power. Thermal solutions should be designed to dissipate this target power level. The thermal design power is specified as the highest sustainable power level of most or all of the real applications expected to be run on the given product, based on extrapolations in both hardware and software technology over the life of the component. Thermal solutions should be designed to dissipate this target power level.
TIM	Thermal Interface Material. This material is designed to fill surface voids between the die and heat sink surfaces in order to facilitate heat transfer.
Tjunction	temperature at the hottest point in the die
MCH	Memory Controller Hub, also referred to as chipset MCH
OEM	Original Equipment Manufacturer

1.3 Reference Documents

Table 1. Related reference documents

Document/Reference Title	Source/Document Number
Intel® Pentium® M Processor For Embedded Applications Thermal Design Guide	http://developer.intel.com/design/intarch/designgd/273885.htm
Intel® 845G/845GL/845GV chipset MCH Thermal Design Guide	http://developer.intel.com/design/chipsets/designex/298655.htm
Intel® 82801DB I/O Controller Hub 4 (ICH4): Thermal and Mechanical Design Guidelines Design Guide	http://developer.intel.com/design/chipsets/designex/298651.htm

Mechanical Reference

2

The Intel® 855GME and Intel 852GME chipset MCHs are constructed with a Flip Chip Ball Grid Array (FCBGA) package with a size of 37.5 mm x 37.5 mm. It includes 732 solder ball lands with a ball pitch of 1.27 mm. The chipset MCH will also include capacitors mounted on the top of the package. Reference drawings are shown in [Figure 1](#) and [Figure 2](#). The drawings are not drawn to scale and the units shown are in millimeters.

The 855GME and 852GME MCH packages will include capacitors on the top-side. The location of capacitors may differ between the 855GME and 852GME MCHs. Care should be taken when applying a thermal solution onto the die in order to avoid any accidental electrical shorts.

2.1 Intel® 855GME and Intel® 852GME Chipset MCH Package

Note: The capacitor locations shown below may not be representative of the exact placement on the 855GME or the 852GME MCH.

Figure 1. 855GME and 852GME chipset MCH Package Dimensions (mm) – Top View

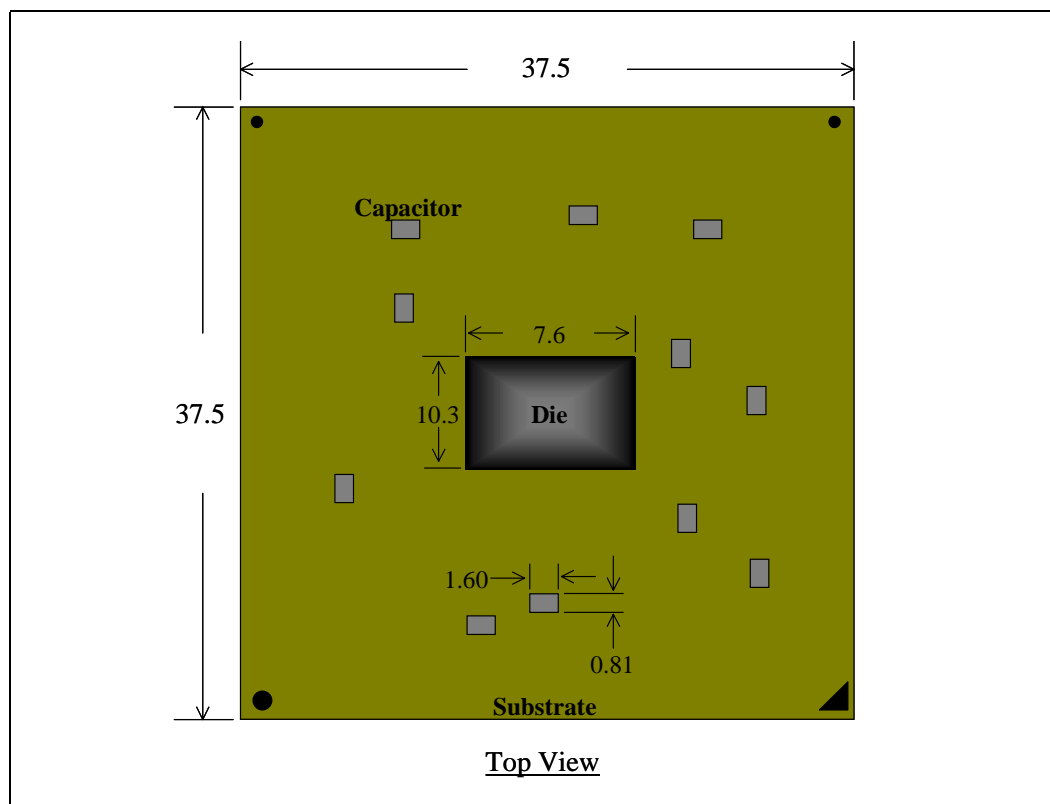
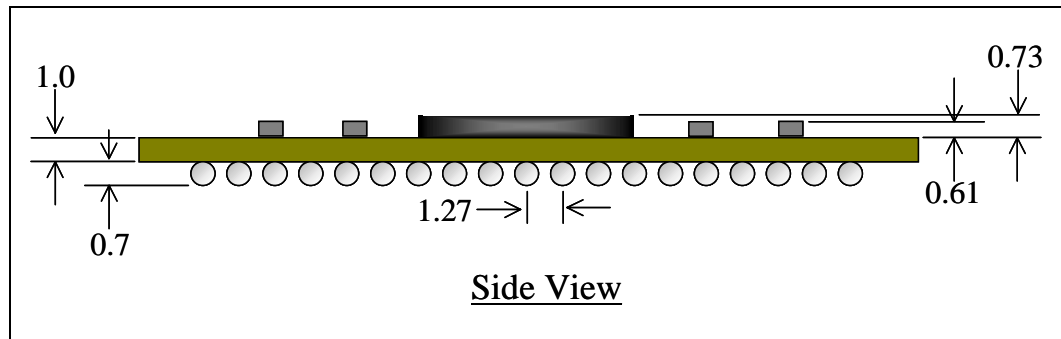


Figure 2. 855GME and 852GME Chipset MCH Package Dimensions (mm) - Side View



Computational Fluid Dynamics (CFD) Modeling

3

3.1 855GM MCH Thermal Model

A Computational Fluid Dynamics (CFD) thermal model of the 855GM chipset MCH has been developed to assist in the characterization of the package thermal limits and the evaluation of cooling methods. The thermal model used in our analysis is based on the package construction shown in Figure 3. Simplified cuboids with the correct material properties are used to model the primary portions of the chipset MCH package as shown in Figure 4. Contact your Intel representative for information on obtaining the CFD model.

Note: The CFD thermal model for the 855GM MCH may also be used for the 855GME and the 852GME chipset MCHs.

Figure 3. Package Construction Overview

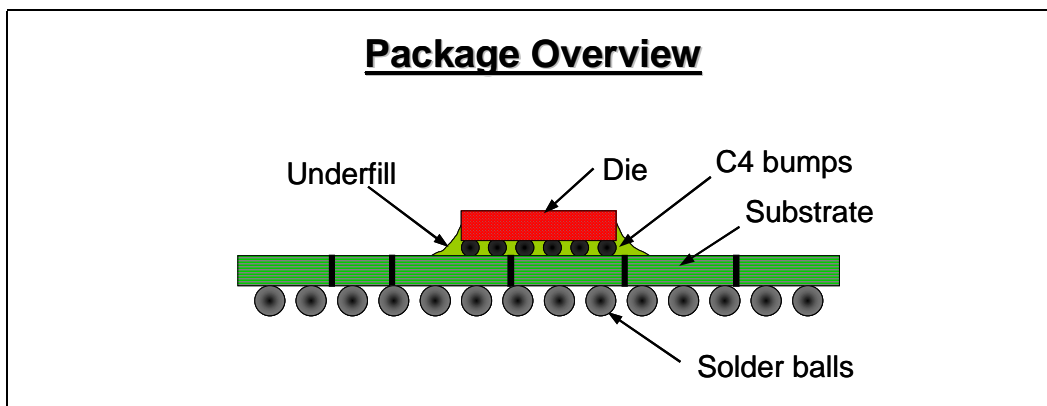
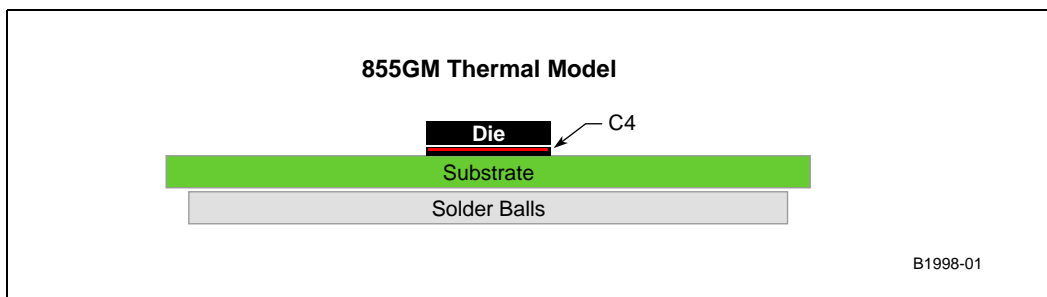


Figure 4. 855GM MCH Thermal Model



3.2 Thermal Design Power (TDP) Values

Use the following thermal design power (TDP) values when modeling based on the configuration that is being simulated. When designing for intermediate configurations on the 855GME MCH, round up to next highest TDP value.

Table 2. 855GME and 852GME MCH Thermal Design Power

SKU	Config	Core VCC (V)	GFX Core (MHz)	DDR (MHz)	Memory Size (Mbytes)	# of DIMMs	# of Rows	LVDS Display Settings	TDP (W)
Intel® 855GME MCH	Max	1.35	250	333	512	2	4	Dual	4.3
	Min	1.2	133	200	256	1	1	Single	2.6
Intel® 852GME MCH	Max	1.5	266	333	512	2	4	Dual	5.7

3.3 Maximum Temperature Specification

Use the following table to determine the maximum junction temperature value when modeling the 855GME or 852GME chipset MCH. The junction temperature is located at the hottest part of the die.

Table 3. 855GME and 852GME Chipset MCHs Maximum Temperature Value

T _{j,max} (°C)
110

3.4 Modeling Assumptions

Computational Fluid Dynamics (CFD) modeling is performed to provide a basis for estimating the behavior of the Intel® 855GME and Intel® 852GME chipset MCHs under varying cooling configurations. Intel provides a Flotherm model of the 855GM and is available through field sales. This model may also be used to simulate the 855GME and 852GME chipset MCHs. The thermal model of the Intel® 855GME and Intel® 852GME chipset MCHs were analyzed in a simulated CompactPCI* blade environment. Assumptions used in the thermal analyses are summarized below. However, please note that they do not represent a specific design recommendation and are mainly used as a basis for the thermal analysis.

The following analysis was performed to evaluate the need for a heatsink to adequately cool the 855GME and 852GME chipset MCHs.

Thermal Modeling Assumptions:

1. Local Ambient Conditions between 40° C and 60° C. Local ambient is specified as the temperature locally surrounding the processor. Most local ambient conditions for embedded applications fall near the middle of that range.
2. Airflow ranges between 50 and 500 LFM.
3. The entire motherboard is modeled as an orthotropic cuboid with an effective thermal conductivity based on the assumed copper content of the motherboard. In the analysis

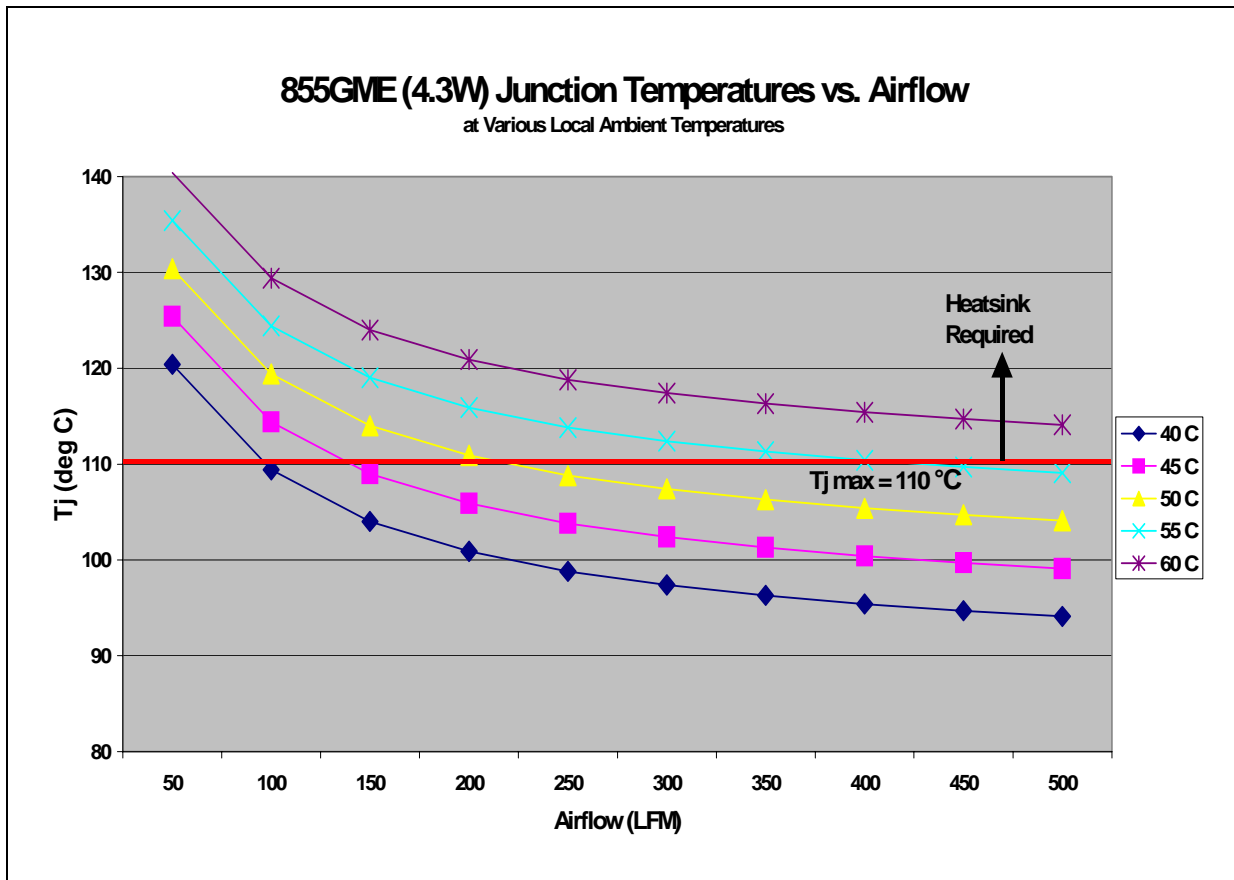
presented the copper content is assumed to be 10 percent of the overall volume of the motherboard.

4. Board-to-board spacing of 0.8”, consistent with the CompactPCI* specification.
5. $T_{j,max}$ for the 855GME and 852GME chipset MCHs is 110 °C.

3.5 Modeling Results – 855GME MCH

Some boundary conditions evaluated will necessitate a heatsink for the 855GME chipset MCH. See Figure 5 for a graph of junction temperature (T_j) vs. airflow (in linear feet per minute) for various local ambient temperature conditions. A heatsink will be needed in all cases where the T_j of the 855GME chipset MCH die is greater than 110 °C.

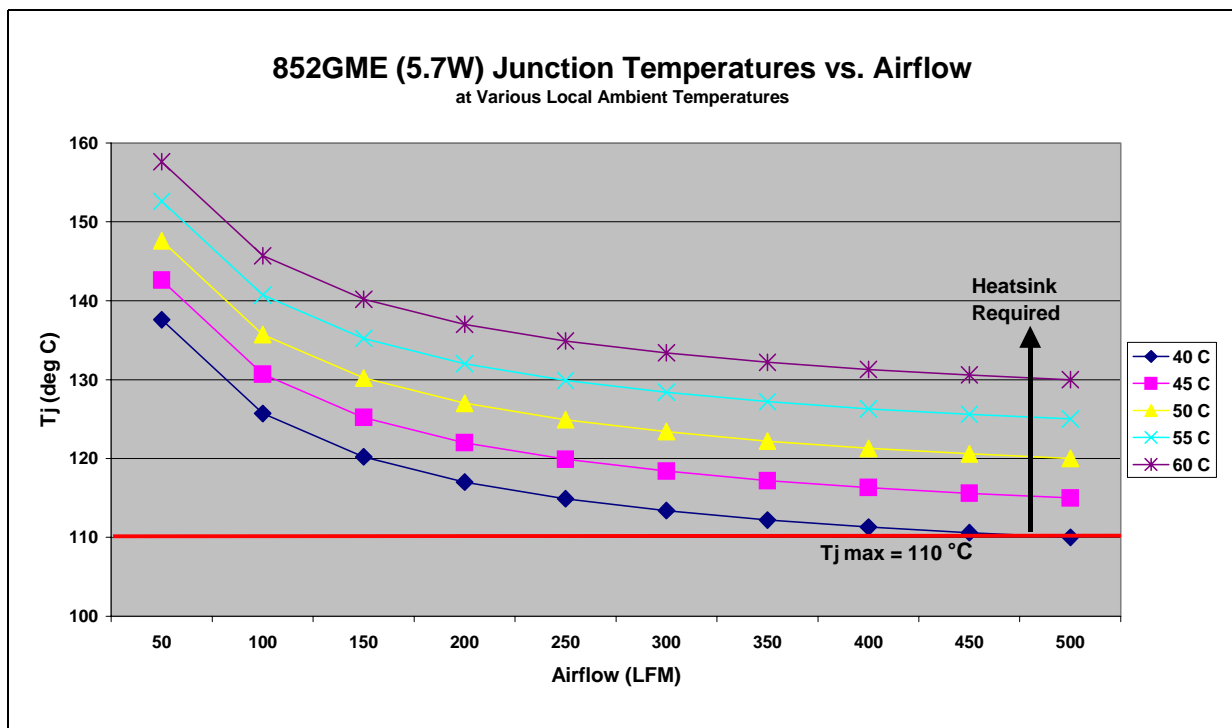
Figure 5. 855GME MCH (4.3W) Junction Temperatures vs. Airflow



3.6 Modeling Results – 852GME

All boundary conditions evaluated will necessitate a heatsink for the 852GME chipset MCH. See Figure 6 for a graph of junction temperature (T_j) vs. airflow for various local ambient temperature conditions. A heatsink will be needed in all cases where the T_j of the 852GME chipset MCH die is greater than 110 °C. Notice that a heatsink is necessary for all cases shown below.

Figure 6. 852GME Airflow Modeling Results



3.7 CFD Modeling Conclusions

The 855GME chipset MCH, under many embedded configurations, will not require a heatsink. However, if your boundary conditions are not sufficient to adequately cool the chipset MCH, Intel offers two reference heatsink designs which are found in sections 4 and 5.

The 852GME chipset MCH will require a heatsink under almost all configurations. Refer to sections 4 and 5 for a reference thermal solution developed by Intel. Both solutions will work with the 852GME.

Reference Thermal Solution for 1U Applications

4

4.1 Applications

The thermal solution referenced in this chapter is valid for both the 855GME and 852GME when the system allows for upwards of 1U (1.75" chassis) in z-height.

Note: Many boundary conditions may permit the 855GME MCH heatsink to be packaged without a thermal solution. The 852GME will require a heatsink in most configurations. See [Section 3](#) for computational fluid dynamics (CFD) modeling where specific boundary conditions are analyzed.

The reference thermal solution is capable of adequately cooling the 855GME or 852GME chipset MCHs at all boundary conditions referenced in [Section 3.4](#).

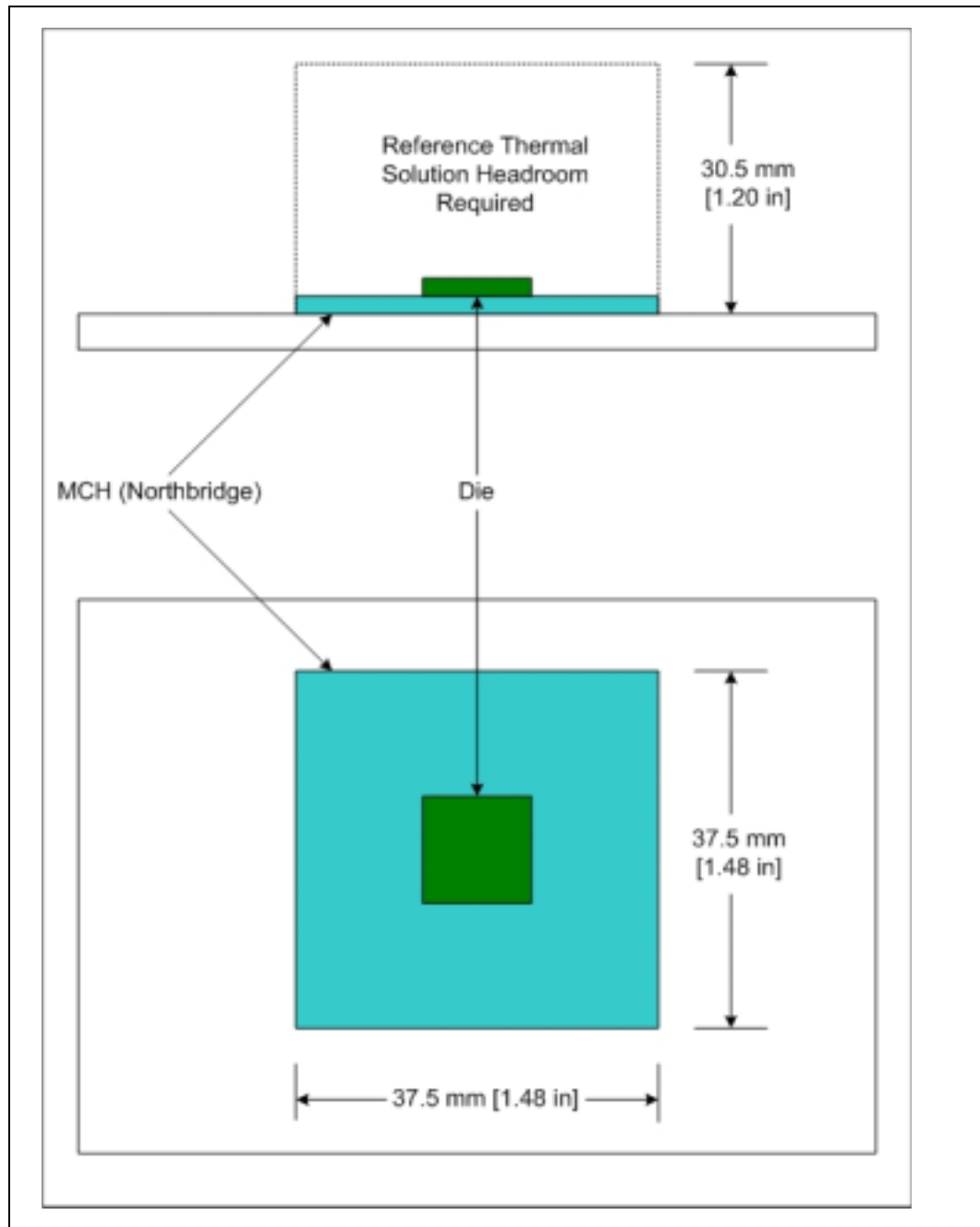
4.2 Required Volumetric Keepout

The 1U thermal solution will require a volumetric keepout region above the chipset MCH. See [Figure 7](#) for a detailed side and top view of the keepout.

[Appendix B, “Mechanical Drawings”](#) contains a detailed board keep-out restriction for the heatsink and mounting clips.

Note that the 1U reference thermal solution for embedded applications is exactly the same as that referenced in the thermal design guide for the Intel® 845G chipset MCH. See [Table 1](#) for location of the Intel® 845G Chipset MCH Thermal Design Guide.

Figure 7. 1U Reference Thermal Solution Volumetric Keepout



4.3 Heatsink Assembly

The 1U heatsink assembly includes the heatsink (with thermal interface material (TIM) and mechanical interface gasket), the clip, and clip lever as shown in Figure 8. This clip attaches to solder down anchors located on the system board.

Figure 9 shows the assembly placement and actuation mechanism.

Figure 8. 1U Heatsink Assembly (Heatsink, Clip Frame, and Clip Lever)

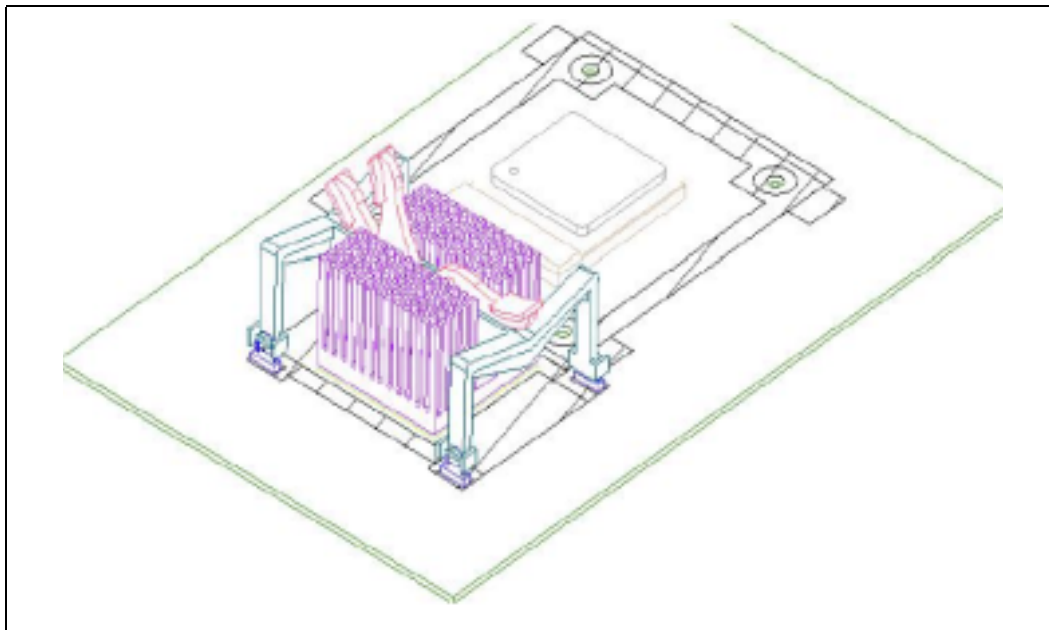
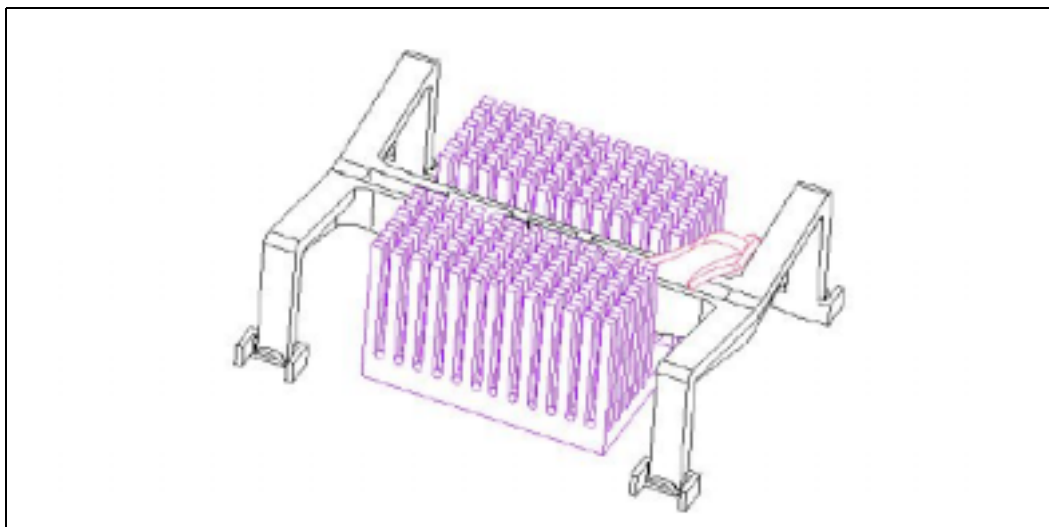


Figure 9. 1U Heatsink Assembly Placement and Actuation



4.4 Mechanical Retention

The heatsink is affixed to the die with a mechanical advantage clip. The clip consists of a clip frame that interfaces to the motherboard through four through-hole mount anchors and an integral lever (see [Figure 12](#)). The clip and lever serve three main purposes:

- Secure the heatsink in intimate contact with the die
- Ensure a thermally good baseline between the die and heatsink
- Prevent damage at the package-to-motherboard solder joint during mechanical shock events

The heatsink must maintain close contact with the die for the life of the system. The generic clip retention mechanism design holds the heatsink to the die through a single point of contact at the center of the heatsink. This ensures that the clip load is centered on the die, thus preventing heatsink tilt that may be caused by unbalanced loading. The clip frame also restrains heatsink lateral motion through tabs located between the heatsink fins (see [Figure 11](#)).

Figure 10. 1U Heatsink Clip Assembly

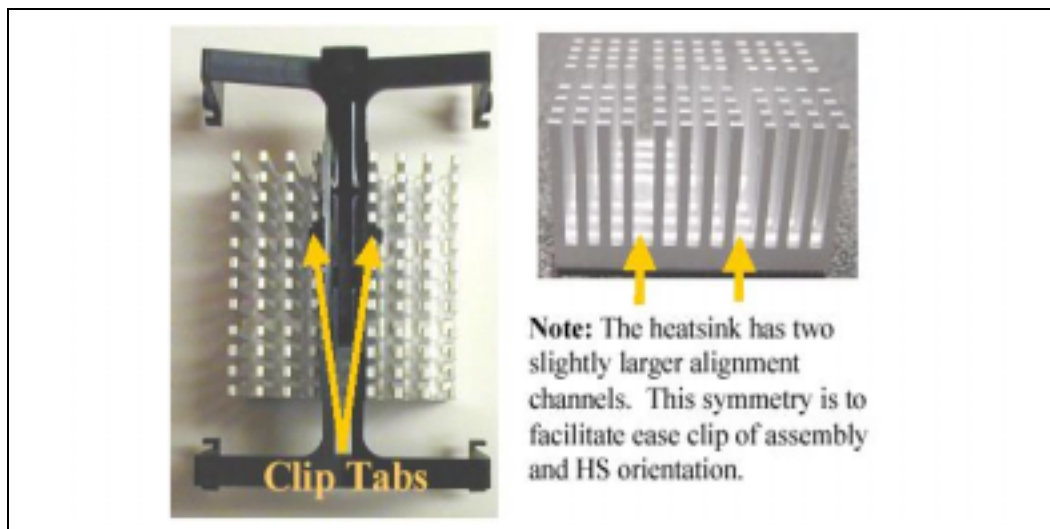
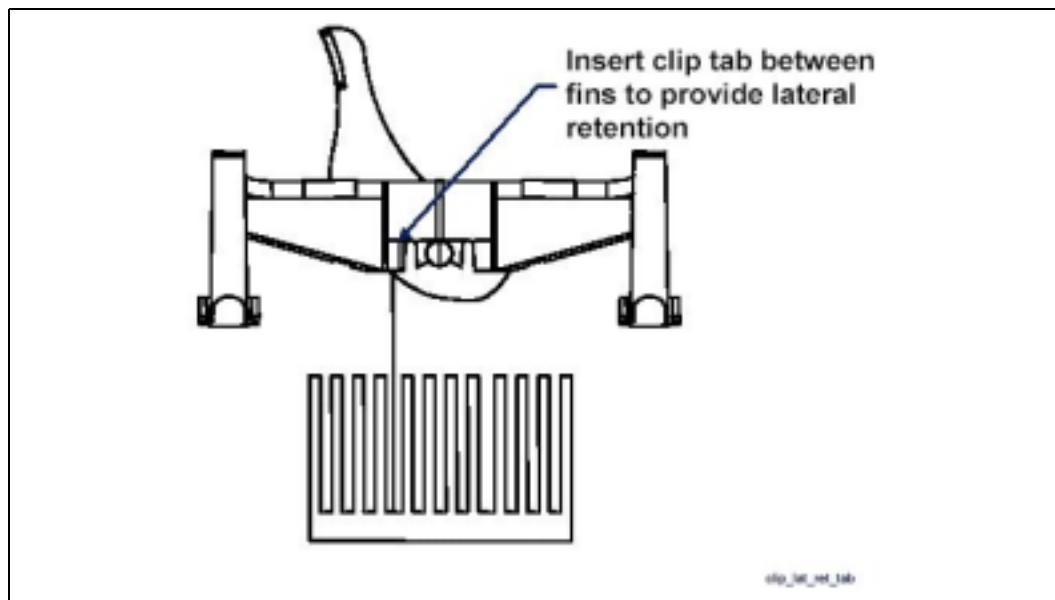


Figure 11. 1U Heatsink Clip Lateral Retention Tab Feature



4.5 Thermal Interface Material (TIM) and Thermal Bond Line

A thermal interface material (TIM) is used to provide improved conductivity between the die and heatsink. The reference thermal solution uses Chomerics® T-710, 0.127 mm (0.005”) thick, 12.7 mm x 12.7 mm (0.5” x 0.5”).

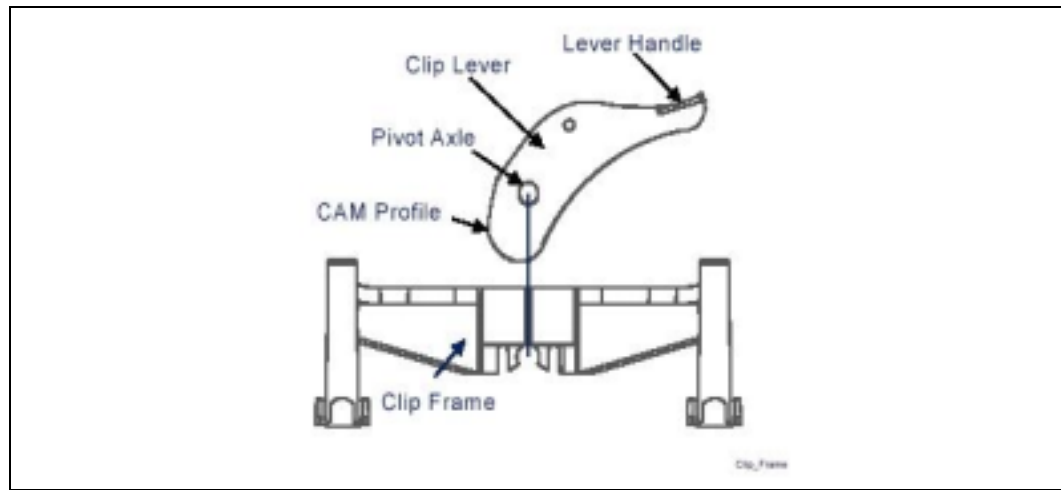
The thickness of the bond line between the heatsink and die is critical to the thermal performance of the TIM. The bond line thickness is dependent on the pressure between the heatsink and the die. The clip retention mechanism is used to generate the pressure required to ensure the thermal performance required. The generic clip frame and lever design generates more than 50-psi pressure.

4.6 Solder Joint Protection

The generic clip design uses mechanical preload on the package to protect the solder joint against damage under mechanical shock. The design features a rotating cam (see Figure 12) that generates substantial preload between the heatsink and package. The cam has a levered handle that provides a mechanical advantage during installation.

The preload serves to compress the solder ball array between the package and the motherboard. The compression in the solder balls delays the onset of the tensile load under critical shock conditions, and the magnitude of the maximum tensile load is thereby reduced. In this manner, the critical solder balls are protected from tensile loading that may cause damage to the solder joint.

Figure 12. 1U Heatsink Clip Frame and Lever



4.7 1U Reference Thermal Solution Mechanical Drawings

Contact your field representative for additional information.

Note: The 1U reference thermal solution presented in this chapter is the same as that referenced in the Intel® 845G Chipset MCH Thermal Design Guide.

Reference Thermal Solution for CompactPCI* and Blade Applications 5

5.1 Applications

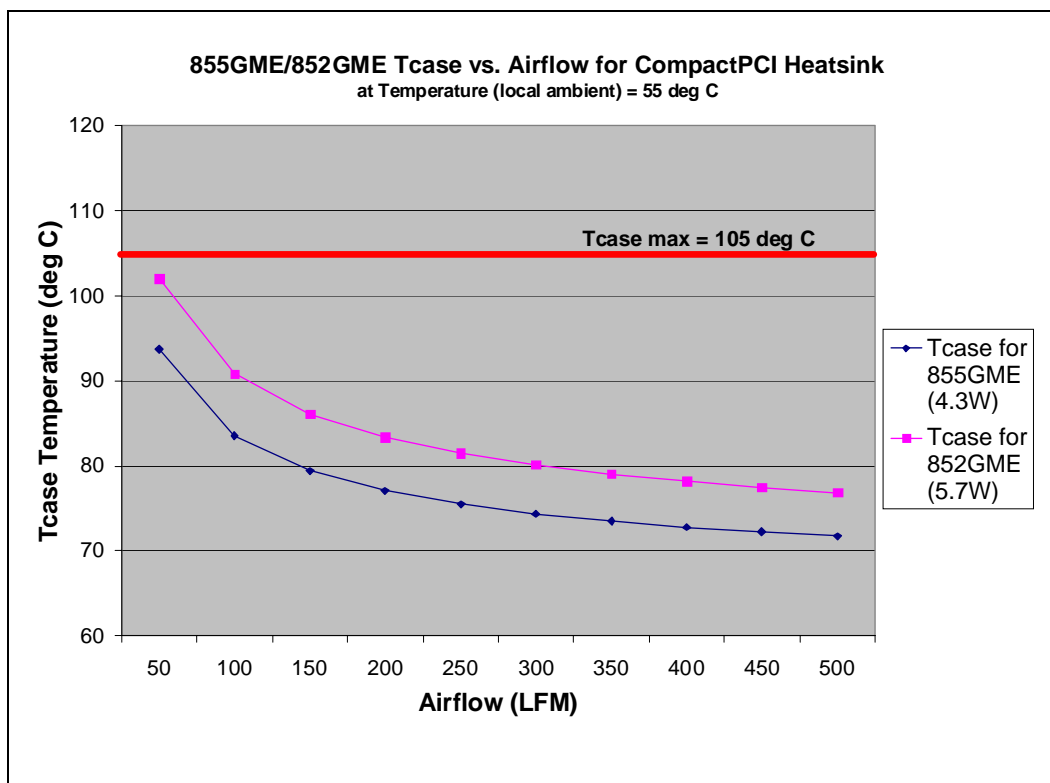
The thermal solution referenced in this chapter is valid for both the 855GME and 852GME chipset MCHs when the application only allows for 0.54” of z-height above the board. Note that many boundary conditions may permit the 855GME MCH to be packaged without a thermal solution. The 852GME will require a heatsink in most configurations. See [Chapter 3](#) for computational fluid dynamics (CFD) modeling where specific boundary conditions are analyzed.

5.2 CompactPCI* Heatsink Thermal Performance

The CompactPCI reference thermal solution is capable of adequately cooling the 855GME or 852GME chipset MCHs at most boundary conditions referenced in [Section 3.4](#).

[Figure 13](#) below shows the thermal performance of the heatsink on both the 855GME and 852GME MCHs at a local ambient temperature (T_{LA}) of 55 °C. For performance at other local ambient temperatures, shift the curve vertically upwards or downwards accordingly. Note that at $T_{LA}=60^{\circ}\text{C}$ with 50 LFM of airflow, this heatsink may not adequately cool the 852GME. For these applications, Intel recommends the use of the 1U thermal solution presented in [Chapter 4](#).

Figure 13. CompactPCI* Heatsink Thermal Performance

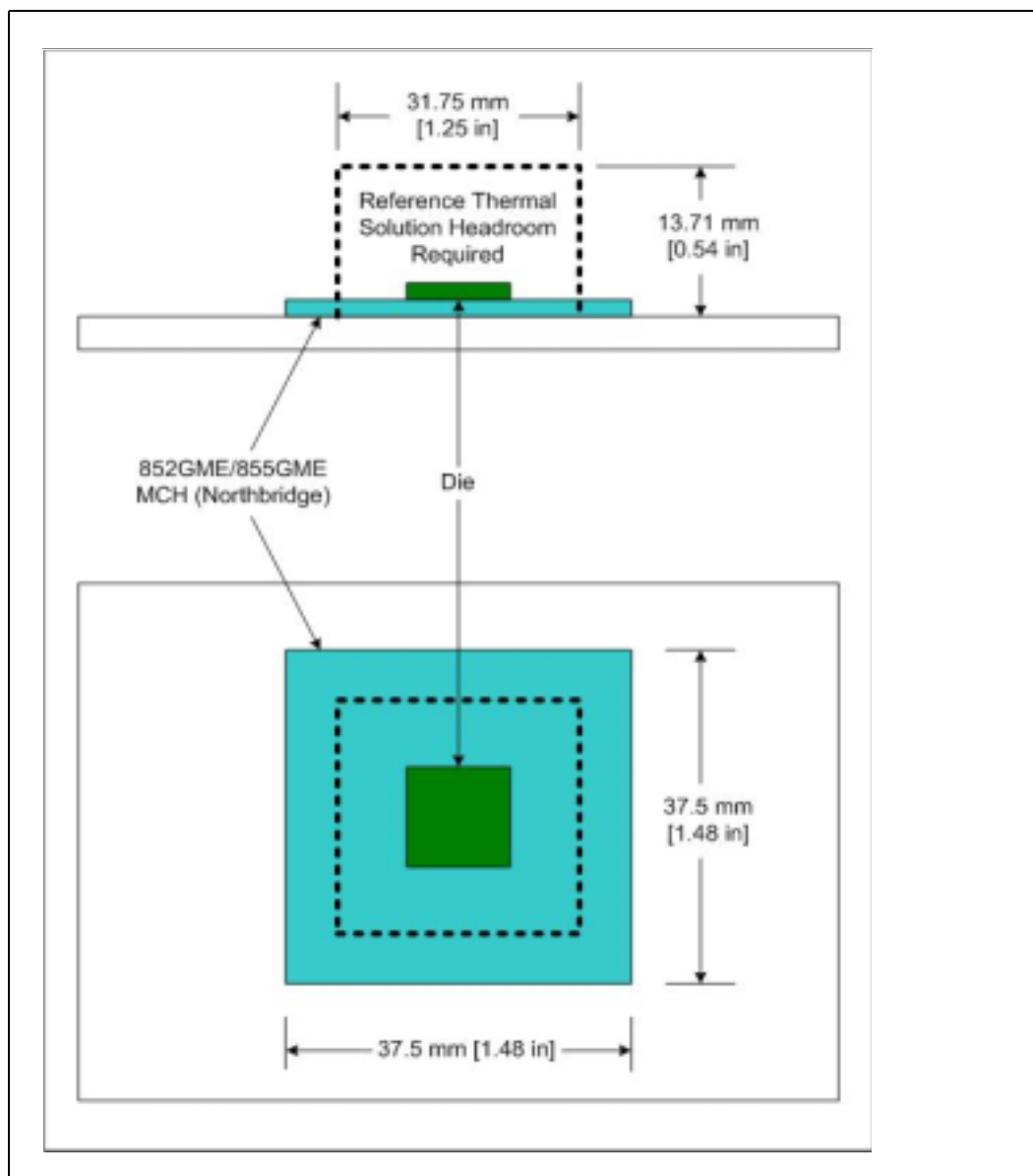


5.3 Required Volumetric Keepout

The CompactPCI* thermal solution will require a volumetric keepout region above the chipset MCH. See Figure 14 for a detailed side and top view of the keepout.

There is not a board keep-out restriction for the CompactPCI* heatsink. It uses an adhesive tape thermal interface material for mechanical retention, and is smaller in footprint than the 855GME and the 852GME chipset MCHs.

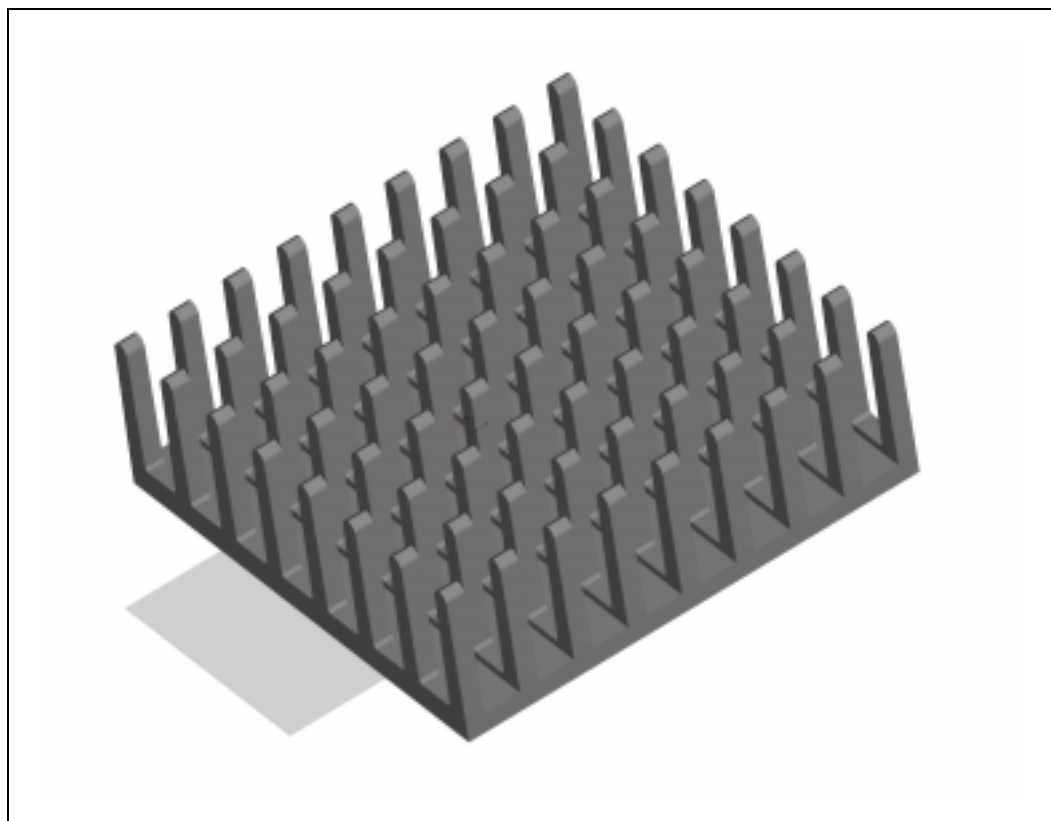
Figure 14. CompactPCI* Thermal Solution Volumetric Keepout



5.4 CompactPCI* Heatsink Assembly

The CompactPCI heatsink assembly includes the heatsink an adhesive tape thermal interface material, and a protective pull-tab as shown in [Figure 15 on page 23](#).

Figure 15. CompactPCI* Heatsink Assembly (Heatsink, Pull-tab, and TIM)



Note: Thermal Interface Material (TIM) is not shown in picture.

5.5 Mechanical Retention

The heatsink is affixed to the die with an adhesive tape thermal interface material. This retention scheme does not require board modifications and can be incorporated at any point in the design cycle, assuming the z-height requirement is met.

5.6 Thermal Interface Material (TIM) and Thermal Bond Line

A thermal interface material (TIM) is used to provide improved conductivity between the die and heatsink. The reference thermal solution uses Chomerics* T411 adhesive tape thermal interface material, 15 mm x 15 mm x 0.254 mm (0.59" x 0.59" x .01").

The thickness of the bond line between the heatsink and die is critical to the thermal performance of the TIM. The bond line thickness is dependent on the pressure between the heatsink and the die. It is imperative that the heatsink is applied to the die with adequate force.

For more information on force required and other important documentation, see the Chomerics website at <http://www.chomerics.com>.

5.7 CompactPCI* Thermal Solution Mechanical Drawings

See [Appendix B, “Mechanical Drawings”](#) for a detailed drawing.

For an official electronic copy, contact Foxconn*. Contact information is available in [Appendix A, “Vendor Information”](#).

Temperature Measurement Metrology 6

6.1 Case Temperature Measurements

Intel has established guidelines for the proper techniques to be used when measuring chipset MCH case temperature. [Section 7.3](#) contains information on running an application program that emulates anticipated TDP.

The surface temperature at the geometric center of the die corresponds to the maximum Tcase.

6.2 0 Degree Angle Attach Methodology

1. Mill a 3.3 mm (0.13") diameter hole centered on bottom of the heatsink base (see [Figure 5](#)). The milled hole should be approximately 1.5 mm (0.06") deep.
2. Mill a 1.3 mm (0.05") wide slot, 0.5 mm (0.02") deep, from the centered hole to one edge of the heatsink. The slot should be in the direction parallel to the heatsink fins (see [Figure 16](#) and [Figure 17](#)).
3. Attach thermal interface material (TIM) to the bottom of the heatsink base.
4. Cut out portions of the TIM to make room for the thermocouple wire and bead. The cutouts should match the slot and hole milled into the heatsink base.
5. Attach a 36 gauge or smaller calibrated K-type thermocouple bead or junction to the center of the top surface of the die using a high thermal conductivity cement. During this step, make sure there is no contact between the thermocouple cement and the heatsink base because any contact will affect the thermocouple reading. It is critical that the thermocouple bead makes contact with the die (see [Figure 17](#)).
6. Attach heatsink assembly to the MCH and route the thermocouple wires out through the milled slot.

Figure 16. 0 Degree Angle Attach Heatsink Modifications (not to scale)

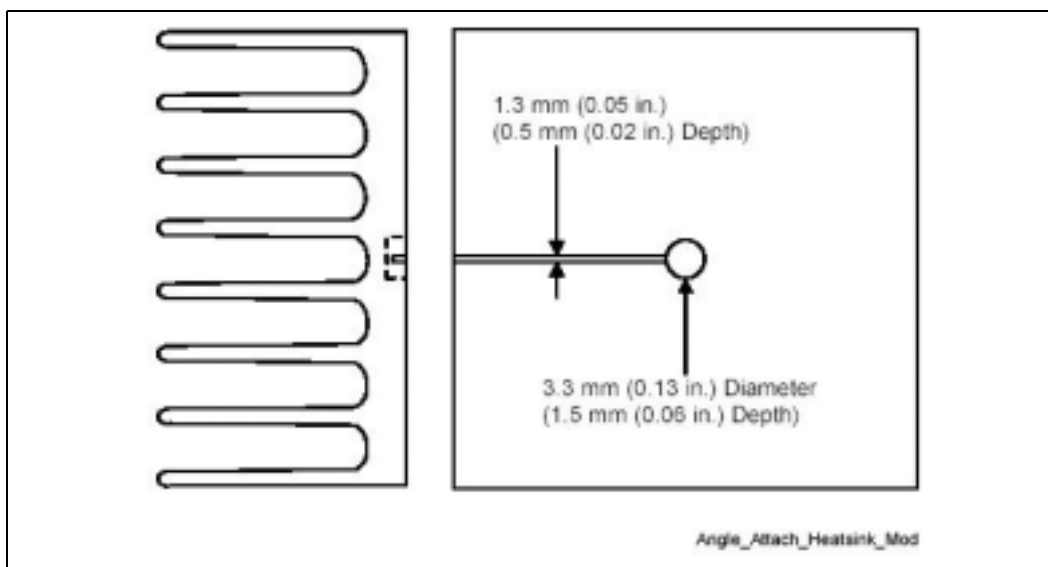
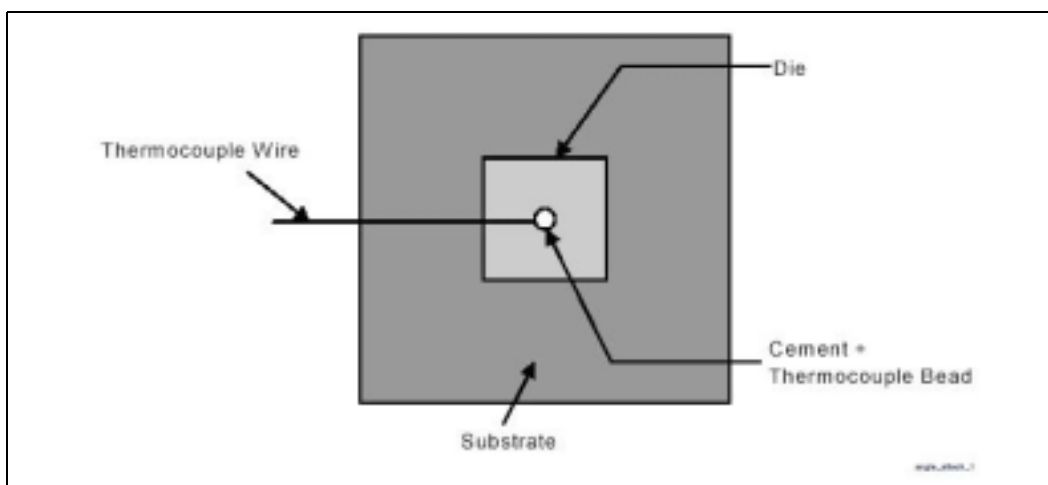


Figure 17. 0 Degree Angle Attach Methodology (not to scale)



6.3 Maximum Temperature Specification

Use Table 4 to determine the maximum temperature value when performing thermal laboratory testing with the 855GME or 852GME chipset MCH using the metrology described in this chapter and the TDP Stress Application. More information about the TDP stress application may be found in Section 7.

Table 4. 855GME and 852GME chipset MCH Maximum Case Temperature Value

T_{case,max} (°C)
105

Thermal Management Features and Tools

7

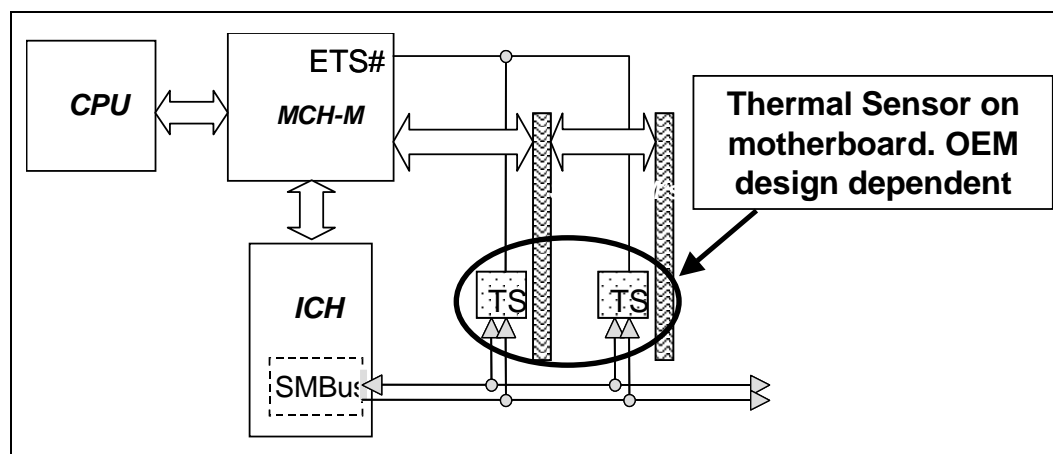
7.1 Internal Temperature Sensor

The Intel® 855GME and 852GME chipset MCH will include an on die temperature sensor that can be used to protect the chipset MCH from exceeding the $T_{j,max}$ specification. Upon detection that the sensor has reached $T_{j,max}$ the chipset MCH will be capable of initiating a bandwidth throttling event that will reduce chipset MCH power and temperature. The sensor will also prove to be useful in optimizing the thermal design for the chipset MCH by being able to provide junction temperature during testing and evaluation of the thermal solution.

7.2 External Temperature Sensor

The chipset MCH is designed to accept an input signal from an external temperature sensor. The external sensor can be placed in a location close to the DDR memory and upon detecting a “hot” condition the chipset MCH would throttle the READ bandwidth. Proper placement of the sensor would have to be determined by the OEM. The OEM would have to characterize the temperature difference between the sensor and the DDR memory devices to determine the best placement for the sensor. On detection of a “hot” condition a signal is communicated directly from the thermal sensor to the MCH via the ETS# pin as shown in Figure 18. The external thermal sensor can be programmed via the SMBus.

Figure 18. External Temperature Sensor



7.3 TDP chipset MCH Stress Application

Intel provides a TDP stress software tool that can be used to validate chipset MCH thermal solutions. The software tool will generate high memory write bandwidths to stress the chipset MCH. The usage model for this software will include the following steps:

1. During the validation phase, OEMs will run this program on their platforms under worse case system loading and environmental conditions. Worse case conditions might include things such as loading the maximum number of rows for memory, setting the operating system to maximum performance mode, an ambient environment at 55° C, and a still air environment with no external air drafts.
2. The TDP stress application will remain running and the junction temperature will be monitored until it has reached steady state. At the completion of the test, if the junction temperature of the chipset MCH does not exceed the maximum operating temperature (110° C) then the thermal solution can be deemed as adequate.
3. If the junction temperature exceeds the maximum operating temperature then this will provide an indication that the thermal solution needs to be improved. Modifications to the thermal solution should be made and the system should be retested until the appropriate junction temperature can be maintained.

The TDP application will also allow the OEM to determine appropriate bandwidth WRITE throttle settings to program into the BIOS.

7.4 Memory Thermal Management Software

The *Intel Memory Thermal Management Software* is a software application that allows OEMs to generate high memory read bandwidths to stress memory. The usage model for this software will include the following steps:

1. Preparation before testing will include placing thermocouples on each of the memory devices of the DDR DIMMs that are to be used during validation.
2. During the validation phase, OEMs will run this program on their platforms under worse case system loading and environmental conditions. Worse case conditions might include things such as loading the maximum number of rows for memory, setting the operating system to maximum performance mode, an ambient environment of 55 °C, and a still air environment with no external air drafts.
3. The program will allow the OEM system designer to test at several different bandwidth throttle settings. Some of the typical settings available for previous chipset MCHs were 65 percent, 55 percent, and 45 percent of the maximum write bandwidth. The OEM can begin by running the test at one of the low bandwidth settings and monitoring the temperatures on the DDR DIMMs. The temperatures should be allowed to reach steady state.
4. Once the temperatures are at steady state the OEM can observe the data and determine whether any of the temperatures have exceeded the maximum allowable temperature for the memory devices. If all the temperatures are within the allowed specification then the OEM can proceed to the next test at a higher bandwidth setting.
5. This process will be repeated until the OEM tests at a bandwidth throttle setting that causes temperature specifications to be exceeded for either the memory devices or the bottom surface. This bandwidth limit will be used to determine the appropriate memory READ throttle setting that can be programmed into the BIOS.

7.5 Thermal Throttling

Both the Intel® 855GME and Intel® 852GME chipset MCHs are available with throttling functionality to protect the chipset MCH from power virus conditions that can cause junction temperatures to increase beyond maximum allowable junction temperatures. Two different methods of thermal throttling are available on the chipset MCH: bandwidth triggered and temperature based throttling.

There are three important things to remember about throttling:

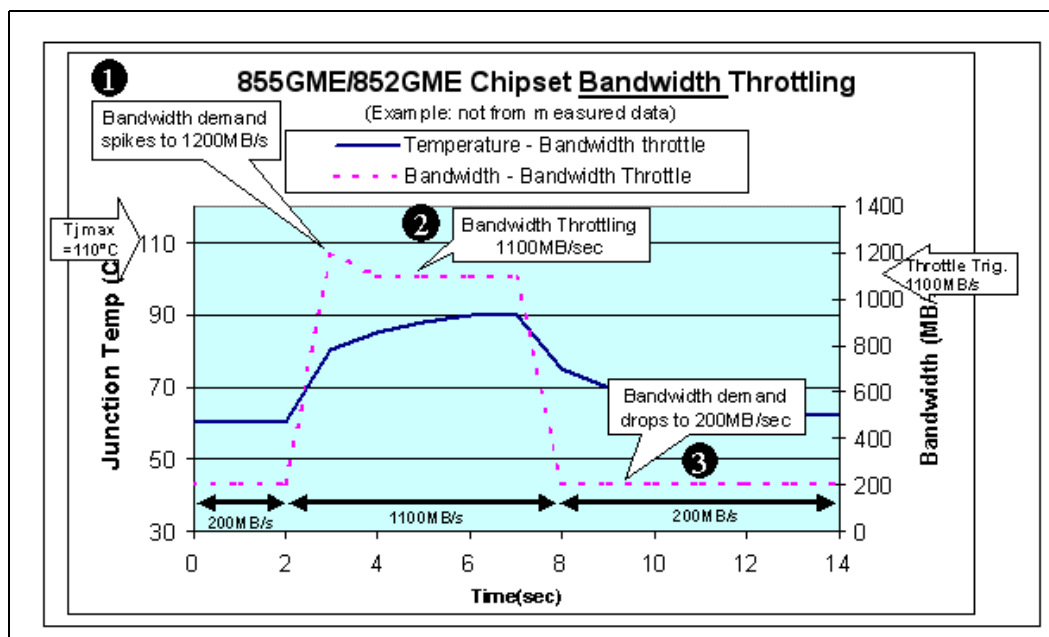
1. It is only intended to be a safeguard to ensure that junction temperatures do not exceed maximum specified junction temperatures.
2. chipset MCH thermal solutions must still be designed to TDP. Throttling is not recommended as a method of designing the chipset MCH cooling capability to levels below TDP.
3. This mechanism was carefully designed to have minimal impact on real applications, while safeguarding against harmful synthetic applications. However, throttling may affect performance of the chipset MCH. Performance of the chipset MCH should be verified by testing with benchmarks.

7.5.1 Bandwidth Triggered Throttling

Bandwidth triggered throttling will limit the maximum bandwidth that can be sustained over long periods as a safeguard against a thermal virus. This method of thermal management will temporarily decrease bandwidth performance of the chipset MCH when an application demands large, sustained bandwidth levels that could cause the chipset MCH to exceed its maximum junction temperature. However, in order to trigger bandwidth throttling, the chipset MCH bandwidth must exceed the threshold over an entire sampling window. Most applications use high bandwidths only in short bursts, and through application analysis, this sampling window has been set large enough so that these applications that create short bursts in bandwidth will not see any throttling. Only a sustained high bandwidth for a period longer than the sampling window has the potential of exceeding thermal limits, and the throttle mechanism is designed to protect the chip against those potentially harmful applications.

Figure 19 below provides a theoretical example of how bandwidth throttling would work. In this example, the bandwidth is set to throttle at 1100 MB/sec. The throttling value would be determined based on the worst case operating conditions. This throttle setting is enabled upon system boot and only one value can be set for the WRITE operations of the chipset MCH. To determine bandwidth, the read/write operations are being monitored continuously by hardware inside the chipset MCH within a one second window.

Figure 19. 855GME/852GME chipset MCH Bandwidth Throttling



1. The system is operating at an idle workload until an application that requires a large amount of bandwidth is initiated. The application demands a peak bandwidth of 1200 MB/sec. for an entire sampling window interval, and it will be reduced to the bandwidth throttle setting limit of 1100 MB/sec. The throttle setting of 1100 MB/sec. effectively places a cap on the allowable bandwidth.

Note: Applications are still allowed to exceed the 1100 MB/sec. limit in short bursts that last less than the sampling window period.

2. The chipset MCH will continue to operate at the throttled amount of 1100 MB/sec. until the application no longer requires this level of sustained bandwidth. In this case the junction temperature has not increased to a temperature that is close to the maximum junction temperature limit of 110° C. So it appears that for the brief period that the large bandwidth level was required the chipset MCH was unnecessarily throttled. A drawback of using bandwidth triggered throttling is that under certain conditions when the system is not operating under worse case conditions the chipset MCH will be throttled regardless of the junction temperature.
3. Once the application stops the system workload will return to a lower workload.

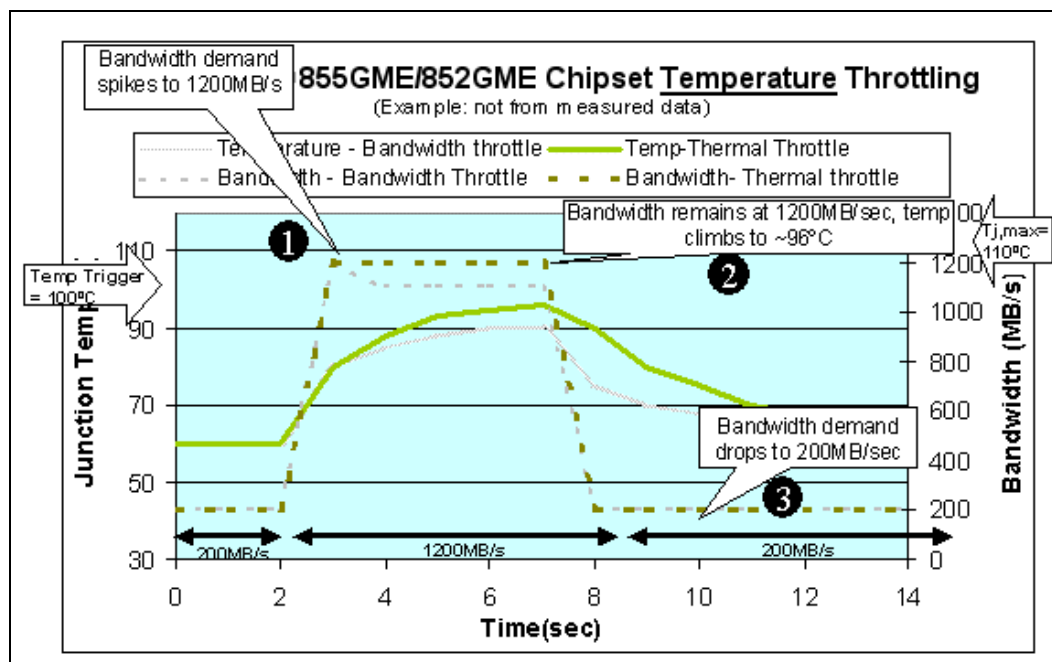
7.5.2 Temperature Triggered Throttling

Temperature triggered throttling will limit the maximum achievable bandwidth as a safeguard against a thermal virus only when the junction temperature reaches a specified trip point temperature. **This method of thermal throttling is an improvement over the bandwidth triggered throttling method because the chipset MCH will only reduce bandwidth performance when it is absolutely necessary under a preset condition.**

The temperature throttle trip point is programmed into the chipset MCH at boot. If the temperature of the chipset MCH goes beyond the trip point limit, the chipset MCH will be throttled to a predetermined maximum throttling amount until the temperature drops below the same temperature limit.

Figure 20 below provides an example of how temperature triggered throttling would optimize throttling under conditions similar to the scenario that was described in Section 7.5.1. In this scenario the hot trip temperature is set at 100 °C. Keep in mind that the $T_{j,max}$ specification for the 855GME and 852GME chipset MCHs is 110 °C and the example described in the section is only intended to illustrate the behavior. The hot trip temperature represents the temperature setpoint at which the chipset MCH will initiate throttling.

Figure 20. 855GME/852GME chipset MCH Temperature Throttling



1. The system is operating at an idle workload until an application that requires a large amount of bandwidth is initiated. The application demands a peak bandwidth of 1200 MB/sec. and the chipset MCH will sustain this bandwidth level until the temperature climbs above the hot trip setting of 100 °C.
2. During this test the chipset MCH operates at a 1200 MB/sec. bandwidth level for a period longer than the sampling window because the junction temperature has not increased above the hot trip point setting. In this case the chipset MCH is demonstrating better bandwidth performance while operating under the same application as in the bandwidth triggering case. This is clearly a preferred method of throttling the chipset MCH only when it is absolutely necessary.

3. Once the application stops the system workload will return to its idle level of 200 MB/sec. In this example, the chipset MCH never required any thermal throttling. The method will potentially allow for large, brief bursts of bandwidth loading without impeding chipset MCH performance.

Thermal/Mechanical Applications

8

8.1 Thermal Interface Materials

Use of a Thermal Interface Material (TIM) between the chipset MCH package and the thermal enhancement is highly recommended to reduce the thermal resistance between the package and the thermal enhancement device. A reduction in the thermal resistance at this interface creates a larger effective thermal conductivity through the interface that improves the thermal capability of the package.

Common types of interface materials include elastomers and phase change materials. These types of materials can easily conform to fill small air gaps that are left between the two interfaces that are mated together. These air gaps can act as insulators and will increase the thermal resistance. An interface material can assist in filling these voids and reducing the thermal resistance at the interface. The total thermal resistance through the interface would consist of the three main resistances:

1. Thermal interface material resistance (θ_{TIM})
2. Contact resistance between the top of the chipset MCH package and the bottom of the thermal interface material ($\theta_{\text{contact-top}}$)
3. Contact resistance between the top of the thermal interface material and the bottom of the heat spreader or heat sink ($\theta_{\text{contact-bottom}}$)

8.1.1 Estimate Thermal Resistance

The thermal resistance of a material can be estimated by using the expression in Equation 1.

The expression provides a result in units of °C/W. If adequate force is applied onto the thermal interface material, it can be assumed the contact resistances are negligible. This is a valid assumption when using the reference design described in [Section 4](#).

Equation: Thermal resistance of a material

$$\theta_{TIM} = \frac{L}{kA}$$

θ_{TIM} = Thermal Resistance through the material (°C/W)

L = thickness of the material (m)

k = thermal conductivity of material (W/m-°C)

A = cross sectional area of the material (m²)

8.2 Mechanical Loading

The pressure applied to the surface of the 855GME or 852GME MCH package should not exceed 100 psi.

If the pressure on the surface of the chipset MCH package is exceeded, problems may arise. The solder ball joints between the package and the motherboard may be subjected to fractures that could result in a loss or degradation of electrical signals from the chipset MCH. Also, the die may be exposed to warpage or, at unusually high levels of stress, cracking.

If a large compressive load is applied to the die surface precautions should be taken to help alleviate some of the load. One manner of doing this is to provide some backing support for the motherboard directly underneath the chipset MCH. Standoffs can be used between the motherboard and the chassis to add rigidity to the motherboard under the chipset MCH and reduce the amount of board flexure under large loads.

8.3 Thermal and Mechanical Reliability

Recommendations for thermal mechanical reliability testing are shown in [Table 5](#). These should be considered as general guidelines. The user should define validation testing requirements based on anticipated use conditions.

Table 5. Reliability Validation

Test ⁽¹⁾	Requirement	Pass/Fail Criteria ⁽²⁾
Mechanical Shock	<ul style="list-style-type: none"> Quantity: three drops for + and – directions in each of three perpendicular axes (i.e., total of 18 drops). Profile: 50 G trapezoidal waveform, 11 ms duration, 170 in/s minimum velocity change. Setup: Mount sample board on test fixture 	Visual Check and Electrical Functional Test
Random Vibration	<ul style="list-style-type: none"> Duration: 10 min/axis, three axes Frequency Range: 5 Hz to 500 Hz Power Spectral Density (PSD) Profile: 3.13 G RMS 	Visual Check and Electrical Functional Test
Power Cycling (for active solutions)	<ul style="list-style-type: none"> 7500 on/off cycles with each cycle specified as 3 minutes on, 2 minutes off at 70 °C 	Visual Check
Thermal Cycling	<ul style="list-style-type: none"> -5 °C to +70 °C, 500 cycles 	Visual Check
Humidity	<ul style="list-style-type: none"> 85% relative humidity, 55 °C, 1000 hours 	Visual Check

NOTES: The above tests should be performed on a sample size of at least 12 assemblies from 3 different lots of material.

Additional Pass/Fail Criteria may be added at the discretion of the user.

Summary

9

The *Intel® 855GME and Intel® 852GME Chipset Memory Controller Hub (MCH) Thermal Design Guide For Embedded Applications* was developed to aid in creating adequate thermal designs that will insure reliable and efficient operation of the 855GME and 852GME chipset MCHs in embedded applications. The goal of this document is to provide an understanding of the operating limits of the chipset MCH in embedded environments and to recommend proper thermal design techniques based on a particular configuration.

Computational Fluid Dynamics (CFD) analysis proved to be a useful tool in providing an initial basis to determine the thermal limits of the chipset MCH under varying cooling configurations. Developing a CFD analysis early in the design stage is highly recommended to assist in identifying potential thermal issues at the individual component and system levels.

Several new features and tools will be made available with the 855GME and 852GME chipset MCH. The chipset MCH will have an on die temperature sensor to assist the thermal control and validation of the thermal solution. It will also have the capability to respond to an input from an external temperature sensor that is placed next the DDR DIMMs. This will allow for improved thermal control of memory temperatures. New software tools will also be provided to validate the thermal solution design at TDP levels and to determine read/write throttle settings.

Vendor Information

A

Table 6. 1U Reference Design Heatsink Assembly Suppliers (as referenced in Section 4)

	Part	Intel Part Number	Supplier	Supplier Part Number
Extruded Heatsink	Pin Fin Heatsink	A54515-001	Foxconn*	
Interface Materials	Chomerics Phase Change TIM (T-710)		Chomerics*	69-12-22066-T710
	Mechanical Interface Material (Poron)	A61203-001	Boyd*	
Attach Hardware	Clip Frame	A65066-001	Foxconn	
	Clip Lever	A67031-001	Foxconn	
	Solder-Down Anchor (4 required per heatsink)	A13494-005	Foxconn	HB96030-DW
Entire Enabling Assembly	MCH Enabling Assembly Includes: Pin fin heatsink, thermal interface material, mechanical interface material, clip frame, and clip lever (does not include solder-down anchors)	A67625-001	Foxconn	PHC029C02012
NOTE: The above reference heatsink vendors and information are identical to that of the Intel® 845G MCH.				

Table 7. CompactPCI* Reference Design Heatsink Assembly Suppliers (as referenced in Section 5)

	Part	Intel Part Number	Supplier	Supplier Part Number
Entire Extruded Heatsink Enabling Assembly	Pin Fin Heatsink with attached Chomerics T411 Adhesive Tape Thermal Interface Material and Pull-Tab	N/A	Foxconn	2ZG85-001A
Heatsink Only	Pin Fin Heatsink	N/A	Foxconn	071-0000-884-1
Thermal Interface Material Only	Chomerics Adhesive Tape TIM (T411)	N/A	Chomerics	

Supplier Contact Information

Boyd Corporation*

- <http://www.boydcorp.com>

Chomerics, Inc.*

- <http://www.chomerics.com>

Foxconn Electronics, Inc.*

458 Lambert Rd.,
Fullerton, CA 92835
Tel: 714-626-1233
Fax: 714-738-8838
<http://www.foxconn.com>

Mechanical Drawings

B

Table 8. Mechanical Drawing List

Drawing Description	Page Number
Board Keep-out Restriction for 1U Reference Design	39
CompactPCI* Heatsink Assembly Drawing	40

Figure 21. Board Keep-Out Region for 1U Reference Design Heatsink and Mounting Anchor Placement

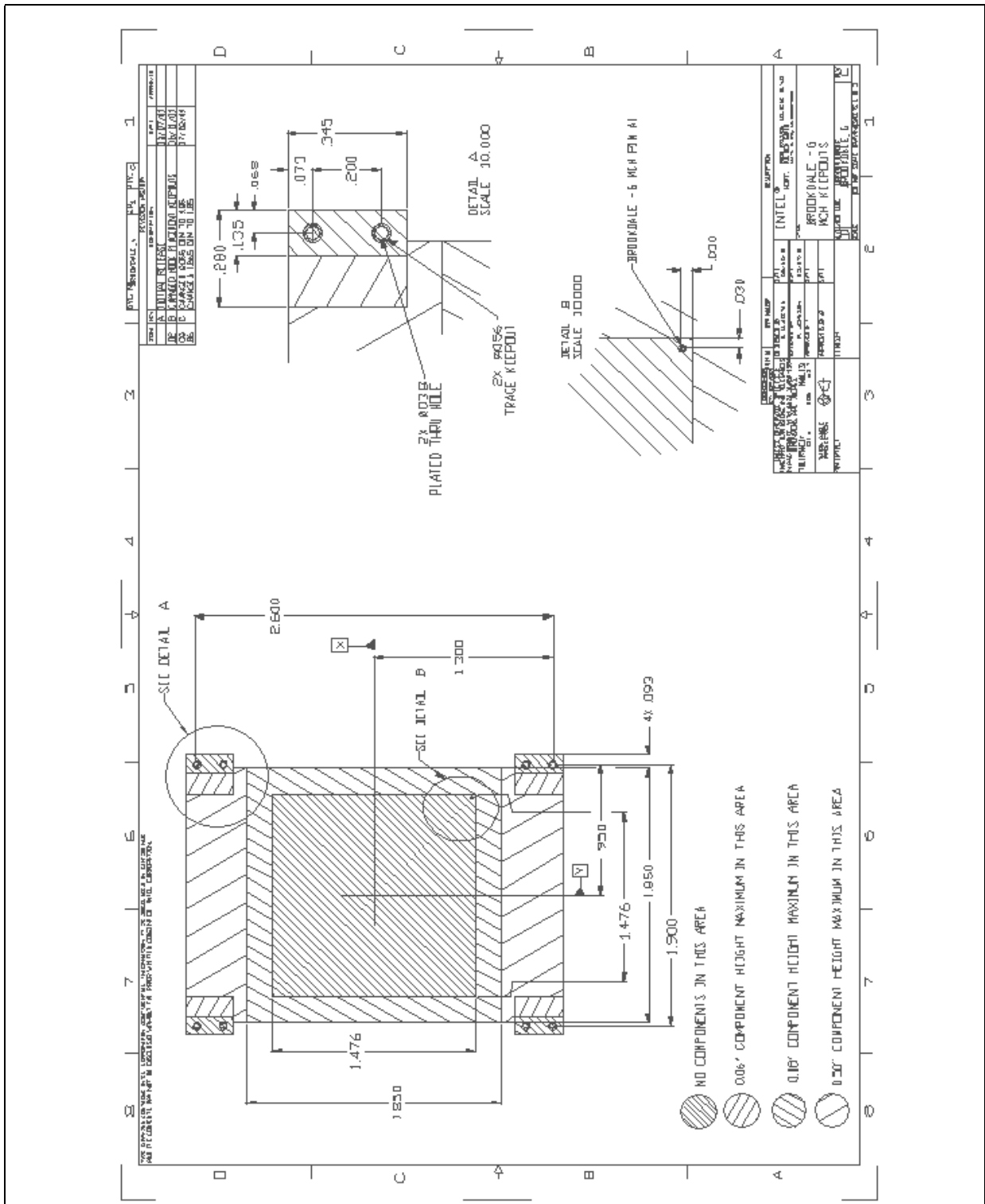


Figure 22. CompactPCI* Heatsink Assembly

